

# Search Notes



Application/Control No.

10/757,782

Examiner

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Applicant(s)/Patent under Reexamination

WUNSH ET AL.

Art Unit

3637

## SEARCHED

Class	Subclass	Date	Examiner
108	28 26 27 12 14 13 40 161	9/14/15	JLC
206	769 770 306		
<del>JPA 2017 5/18/16 JLC</del>			
<del>JPA 2019 1/14/16 JLC</del>			

## INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

## SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
Long base Gr. Fin 1007-ART	9/14/15	JLC
<del>JPA 2017</del>	<del>5/18/16</del>	<del>JLC</del>